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Application/Control No.	Applicant(s)/Patent under Reexamination	
10/660,167	DAY ET AL.	
Examiner	Art Unit	
Michael D. Pham	2167	

SEARCHED				
Class	Subclass	Date	Examiner	
707	1-4	8/23/2006	MP	
707	100-101	8/23/2006	MP	
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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SEARCH NOT (INCLUDING SEARCH		
	DATE	EXMR
updated east search	8/23/2006	MP
updated inventor search	8/23/2006	MP
101 help panel	8/23/2006	MP
Pat Salce (TC2100 SPRE)	8/23/2006	MP
Updated plus Search	8/23/2006	MP
Fast and Focused Search	8/23/2006	MP
Debbie Le (Primary Examiner) Art Unit 2168	8/23/2006	MP
Etienne Primary 2161 Leroux	8/30/06	M.P.